<u>VERSION WITH MARKINGS TO SHOW CHANGES MADE</u>

In the Specification:

Page 16, lines 13 through 27, replace with the following:

Subsequently, the signs of all the [detect] <u>defect</u> candidates in the signed two-time judged defect candidate map 208 are judged in step 209, and the defect candidate 61F with one of the signs (in this case +) is left as a defect candidate. As for the defect candidates 62F and 63F with the other sign (in this case -), the absolute values of the signed differential images thereof <u>provided in step 203</u> are compared <u>in step 210</u> with the second threshold value that is greater than the first threshold value, and included among the defect candidates if the second threshold value is exceeded. In this manner, the one-bit defect candidate map can be finally obtained. When the absolute values of the signed differential images of the defect candidates 62F and 63F are less than the second threshold value, the defect candidate map as shown in FIG. 8F is obtained.

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